Search Notes



10/722,807

Examiner

David Faber

Applicant(s)/Patent under Reexamination

LEHIKOINEN ET AL.

Art Unit

2178

	SEARCHED				
Class	Subclass	Date	Examiner		
715	501.1, 513	2/24/2006	DF		
709	245, 246	2/24/2006	DF		
707	10	2/24/2006	DF		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (Search Notes Attached)	2/24/2006	V	
PLUS (Search Notes Attached)	2/24/2006	VP	
Consulted with Primary Examiner William Bashore	2/24/2006	V	
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